



# Monolithic N-Channel JFET Duals

PRODUCT SUMMARY				
Part Number	V <sub>GS(off)</sub> (V)	V <sub>(BR)GSS</sub> Min (V)	g <sub>fs</sub> Min (mS)	V <sub>GS1</sub> - V <sub>GS2</sub>   Max (mV)
SST421NL	-0.4 to -2	-40	0.3	10
SST423NL	-0.4 to -2	-40	0.3	25

### FEATURES

- Anti Latchup Capability
- Monolithic Design
- High Slew Rate
- Low Offset/Drift Voltage
- Low Gate Leakage: 0.6 pA
- Low Noise
- High CMRR: 102 dB

### BENEFITS

- External Substrate Bias—Avoids Latchup
- Tight Differential Match vs. Current
- Improved Op Amp Speed, Settling Time Accuracy
- Minimum Input Error/Trimming Requirement
- Insignificant Signal Loss/Error Voltage
- High System Sensitivity
- Minimum Error with Large Input Signals

### APPLICATIONS

- Ultralow Input Current Differential Amps
- High-Speed Comparators
- Impedance Converters

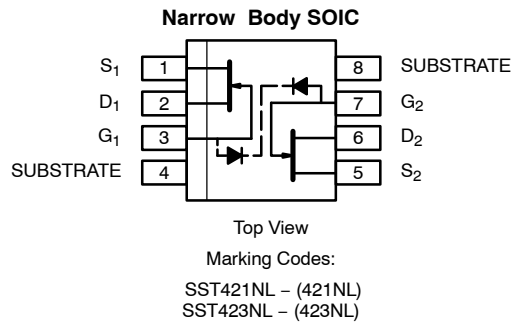
### DESCRIPTION

The SST421NL/423NL are monolithic dual n-channel JFETs designed to provide very high input impedance for differential amplification and impedance matching. Among its many unique features, this series offers low operating gate current.

The SO-8 package provides ease of manufacturing, and the symmetrical pinout prevents improper orientation. The SO-8 package is available with tape-and-reel options for compatibility with automatic assembly methods.

Pins 4 and 8 on SST421NL/423NL part numbers enable the substrate to be connected to a positive polarity, external bias (V<sub>DD</sub>) to avoid latchup.

Similar versions of these part numbers are available in the hermetically sealed TO-78 package. Full military processing is available. See data sheets for part numbers U421/423.



### ABSOLUTE MAXIMUM RATINGS

Gate-Drain, Gate-Source Voltage ..... -40 V  
 Gate-Gate Voltage ..... ±40 V  
 Gate Current ..... 10 mA  
 Lead Temperature (1/16" from case for 10 sec.) ..... 300 °C  
 Storage Temperature ..... -65 to 200 °C  
 Operating Junction Temperature ..... -55 to 150 °C

Power Dissipation : Per Side<sup>a</sup> ..... 300 mW  
 Total<sup>b</sup> ..... 500 mW

- Notes  
 a. Derate 2.4 mW/°C above 25 °C  
 b. Derate 4 mW/°C above 25 °C

SPECIFICATIONS (T <sub>A</sub> = 25 °C UNLESS OTHERWISE NOTED)								
Parameter	Symbol	Specific Test Conditions	Typ <sup>a</sup>	Limits				Unit
				SST421NL		SST423NL		
				Min	Max	Min	Max	
<b>Static</b>								
Gate-Source Breakdown Voltage	V <sub>(BR)GSS</sub>	I <sub>G</sub> = -1 μA, V <sub>DS</sub> = 0 V	-60	-40		-40		V
Gate-Gate Breakdown Voltage	V <sub>(BR)G1 - G2</sub>	I <sub>G</sub> = ± 1 μA, I <sub>D</sub> = 0, I <sub>S</sub> = 0	± 55	± 40		± 40		
Gate-Source Cutoff Voltage	V <sub>GS(off)</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 1 nA	-1.2	-0.4	-2	-0.4	-2	
Saturation Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = 10 V, V <sub>GS</sub> = 0 V	400	60	1000	60	1000	μA
Gate Reverse Current	I <sub>GSS</sub>	V <sub>GS</sub> = -20 V, V <sub>DS</sub> = 0 V	-0.6		-50		-50	pA
		T <sub>A</sub> = 125 °C	-0.3		-50		-50	nA
Gate Operating Current	I <sub>G</sub>	V <sub>DG</sub> = 10 V, I <sub>D</sub> = 30 μA	-1.0					pA
Drain-Source On-Resistance	r <sub>DS(on)</sub>	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 10 μA	2000					Ω
Gate-Source Voltage	V <sub>GS</sub>	V <sub>DG</sub> = 10 V, I <sub>D</sub> = 30 μA	-0.8		-1.8		-1.8	V
Gate-Source Forward Voltage	V <sub>GS(F)</sub>	I <sub>G</sub> = 1 mA, V <sub>DS</sub> = 0 V	0.7					
<b>Dynamic</b>								
Common-Source Forward Transconductance	g <sub>fs</sub>	V <sub>DS</sub> = 10 V, V <sub>GS</sub> = 0 V, f = 1 kHz	0.6	0.3	1.5	0.3	1.5	mS
Common-Source Output Conductance	g <sub>os</sub>		4		10		10	μS
Common-Source Forward Transconductance	g <sub>fs</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 30 μA, f = 1 kHz	0.2	0.12	0.35	0.12	0.35	mS
Common-Source Output Conductance	g <sub>os</sub>		0.4		3		3	μS
Common-Source Input Capacitance	C <sub>iss</sub>	V <sub>DS</sub> = 10 V, V <sub>GS</sub> = 0 V, f = 1 MHz	1.4		3		3	pF
Common-Source Reverse Transfer Capacitance	C <sub>rss</sub>		0.7		1.5		1.5	
Equivalent Input Noise Voltage	$\bar{e}_n$	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 30 μA, f = 10 Hz	30					nV/ √Hz
<b>Matching</b>								
Differential Gate-Source Voltage	V <sub>GS1</sub> - V <sub>GS2</sub>	V <sub>DG</sub> = 10 V, I <sub>D</sub> = 30 μA			10		25	mV
Gate-Source Voltage Differential Change with Temperature	$\frac{\Delta V_{GS1} - V_{GS2} }{\Delta T}$	V <sub>DG</sub> = 10 V, I <sub>D</sub> = 30 μA T <sub>A</sub> = -55 to 125 °C			10		40	μV/°C
Common Mode Rejection Ratio	CMRR	V <sub>DG</sub> = 10 to 20 V, I <sub>D</sub> = 30 μA	102	90		80		dB

## Notes

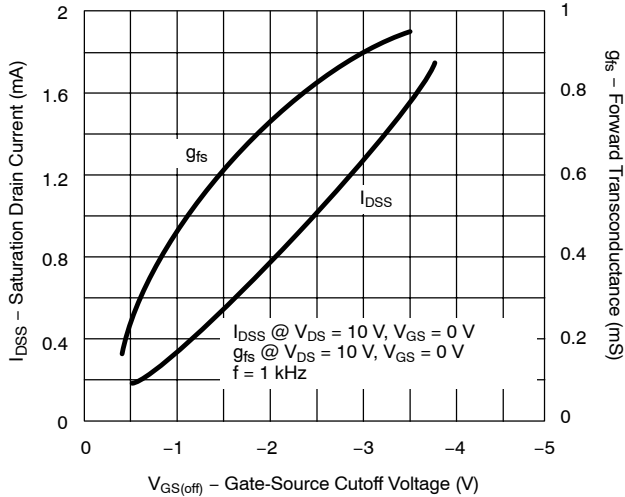
a. Typical values are for DESIGN AID ONLY, not guaranteed or subject to production testing.

NNT

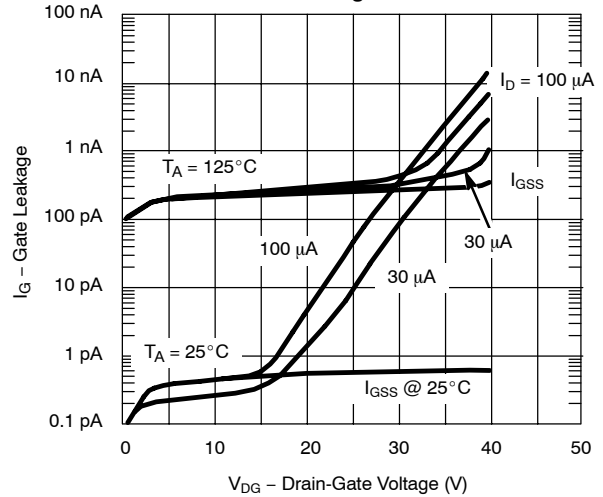


**TYPICAL CHARACTERISTICS ( $T_A = 25^\circ\text{C}$  UNLESS OTHERWISE NOTED)**

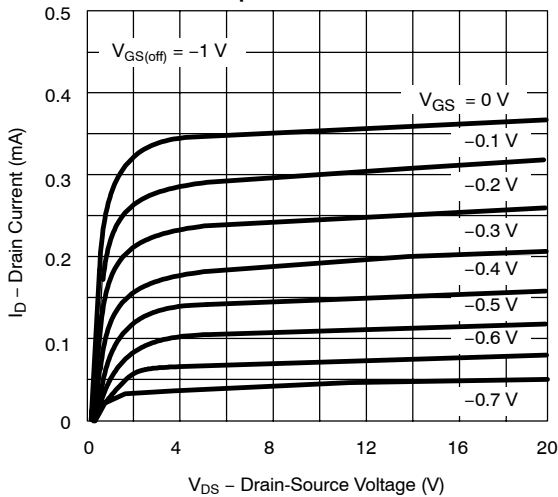
**Drain Current and Transconductance vs. Gate-Source Cutoff Voltage**



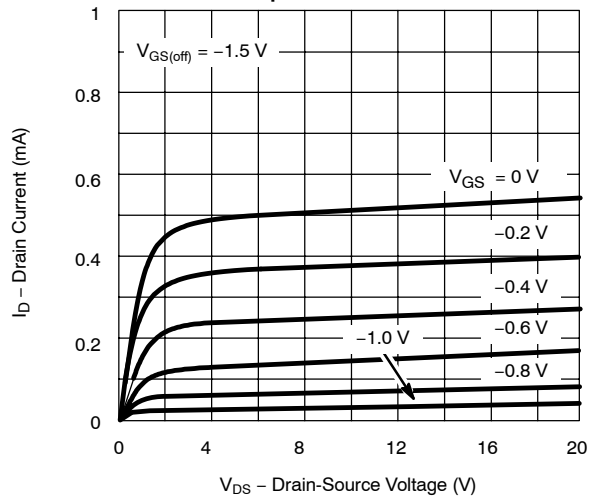
**Gate Leakage Current**



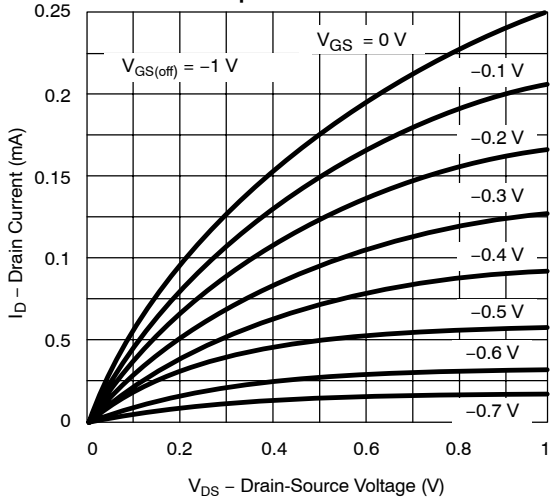
**Output Characteristics**



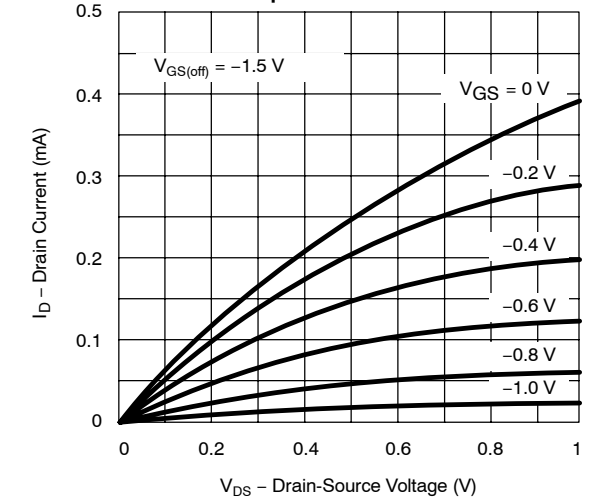
**Output Characteristics**



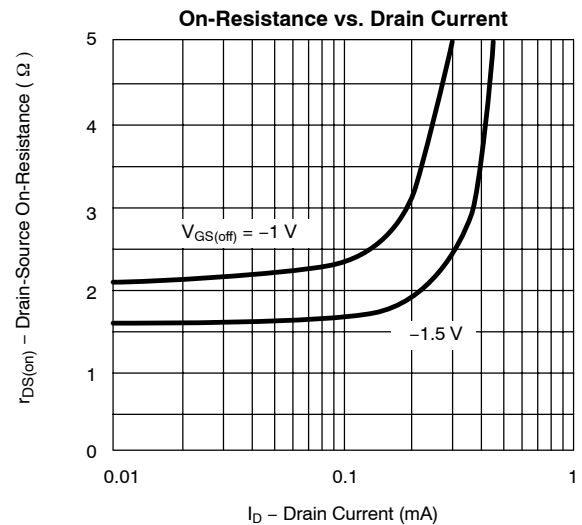
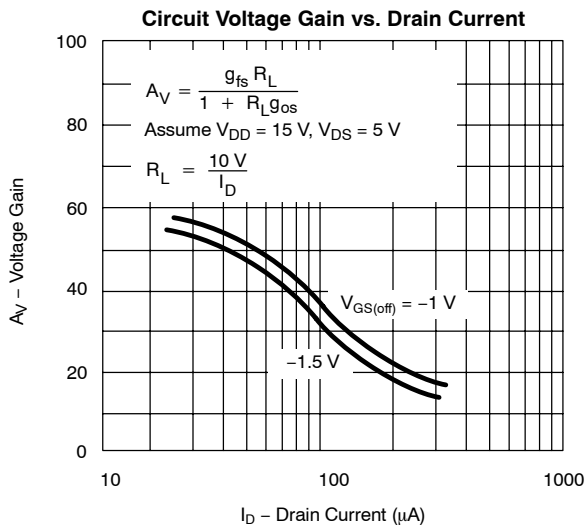
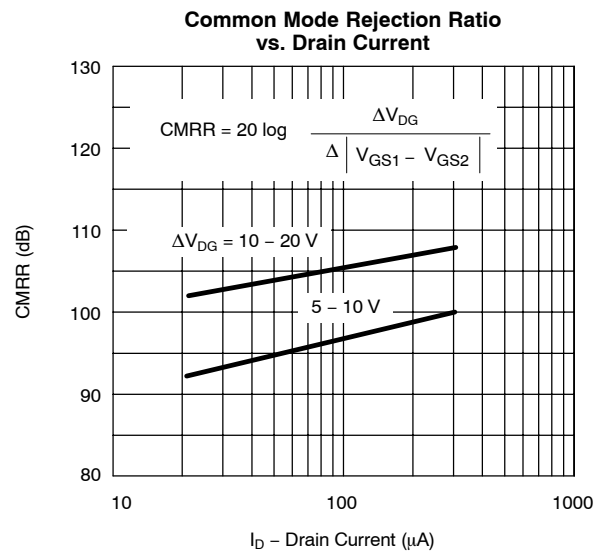
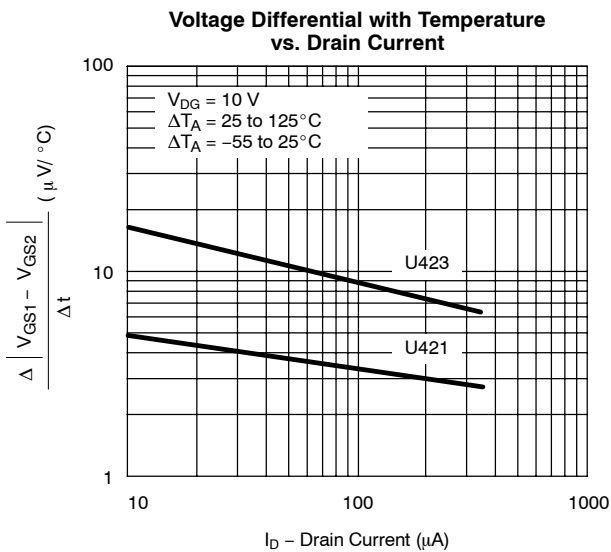
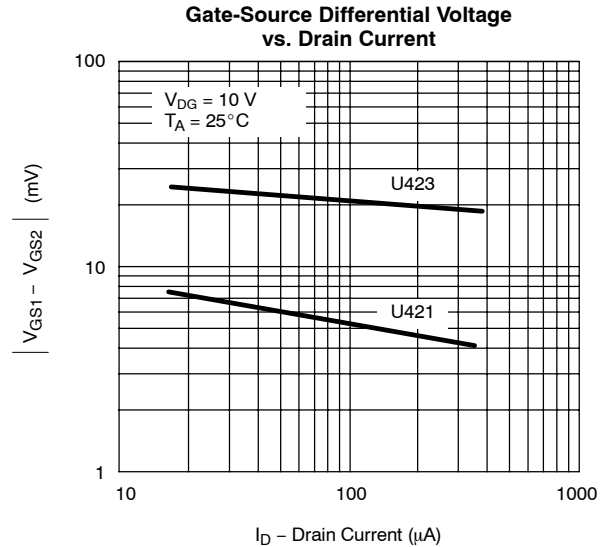
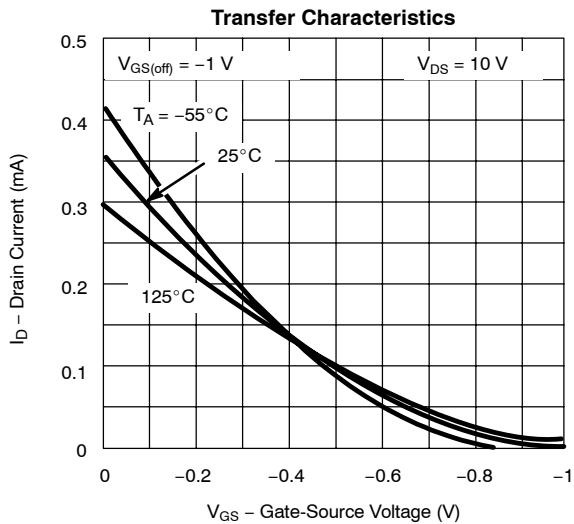
**Output Characteristics**



**Output Characteristics**



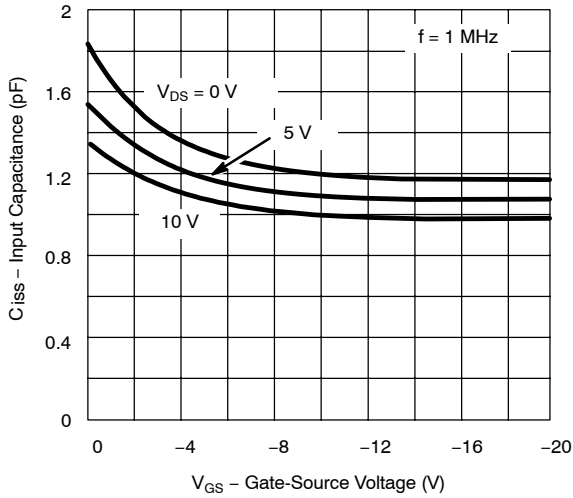
### TYPICAL CHARACTERISTICS ( $T_A = 25^\circ\text{C}$ UNLESS OTHERWISE NOTED)



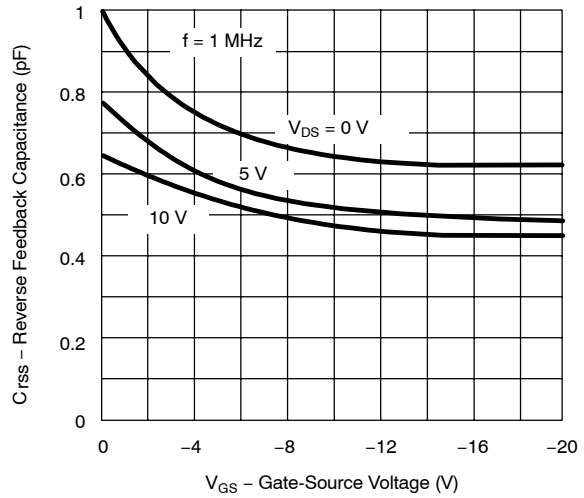


**TYPICAL CHARACTERISTICS ( $T_A = 25^\circ\text{C}$  UNLESS OTHERWISE NOTED)**

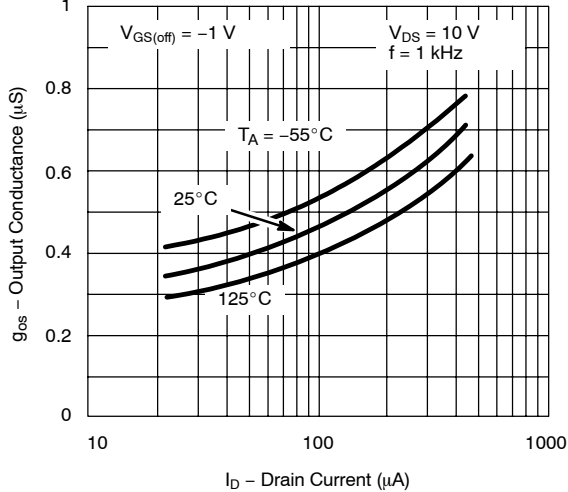
**Common-Source Input Capacitance vs. Gate-Source Voltage**



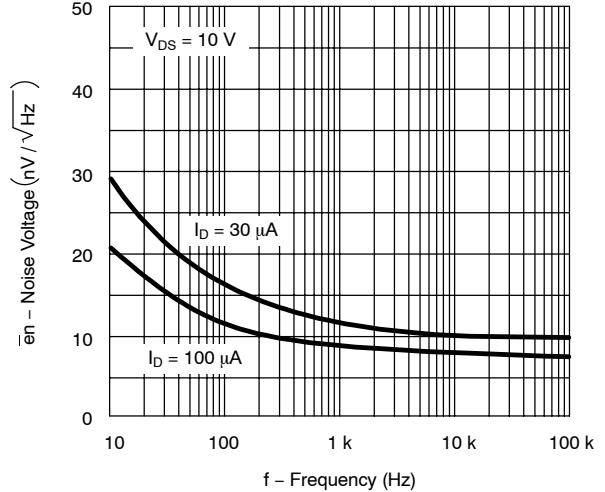
**Common-Source Reverse Feedback Capacitance vs. Gate-Source Voltage**



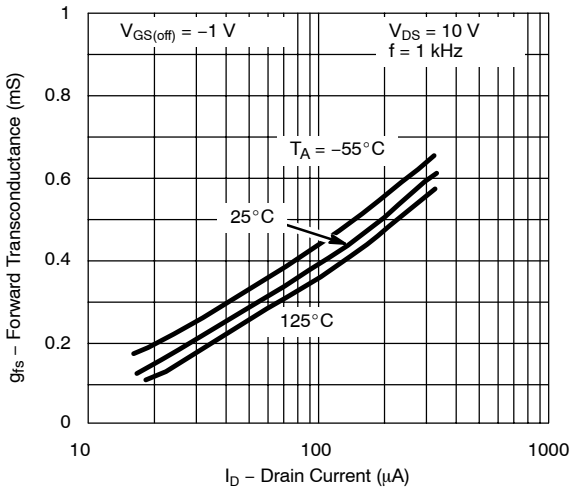
**Output Conductance vs. Drain Current**



**Equivalent Input Noise Voltage vs. Frequency**



**Common-Source Forward Transconductance vs. Drain Current**



**On-Resistance and Output Conductance vs. Gate-Source Cutoff Voltage**

